

2009 15th IEEE International On-Line Testing Symposium (IOLTS 2009)

**Sesimbra-Lisbon, Portugal
24 – 26 June 2009**

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**IEEE Catalog Number: CFP09OLT-PRT
ISBN: 978-1-4244-4596-7**

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IEEE Catalog Number:	CFP09OLT-PRT
ISBN 13:	978-1-4244-4596-7
Library of Congress No.:	2009904088

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Contents

Welcome Message from the General Co-Chairs and Program Co-Chairs

IOLTS 2009 Committees

Program Committee

Keynote Talks

Test Technology Educational Program (TTEP) 2009

Tutorial

General Information

TTTC: Test Technology Technical Council

Session 1 — Aging Monitoring and Analysis

Aging Analysis of Circuit Timing Considering NBTI and HCI 3
D. Lorenz, G. Georgakos and U. Schlichtmann

Built-In Aging Monitoring for Safety-Critical Applications 9
J. C. Vazquez, V. Champac, A. M. Ziesemer Jr., R. Reis, I. C. Teixeira, M. B. Santos and J. P. Teixeira

An I-IP Based Approach for the Monitoring of NBTI Effects in SoCs 15
C. Guardiani, A. Shibkov, A. Brambilla, G. Storti Gajani, D. Appello, F. Piazza and P. Bernardi

A Methodology for Measuring Transistor Ageing Effects Towards Accurate Reliability Simulation 21
E. Maricau and G. Gielen

Session 2 — Transient Faults Evaluation and Analysis

Comparing Transient-Fault Effects on Synchronous and on Asynchronous Circuits 29
R. Possamai Bastos, Y. Monnet, G. Sicard, F. Kastensmidt, M. Renaudin and R. Reis

Invariant Checkers: An Efficient Low Cost Technique for Run-time Transient Errors Detection 35
C. Noro Grando, C. Arthur Lisboa, A. Freitas Moreira and L. Carro

Towards Automated Fault Pruning with Petri Nets 41
P. Maistri and R. Leveugle

Session 3 — System-Level Reliability and Security

A Low-Cost Solution for Developing Reliable Linux-based Space Computers for On-Board Data Handling 49
M. Violante and M. L. Esposti

Nonlinear Compression Functions using the MISR Approach for Security Purposes in Automotive Applications <i>E. Böhl and P. Duplys</i>	55
Improving Yield of Torus NoCs Through Fault- Diagnosis-and-Repair of Interconnect Faults <i>C. Concatto, P. Almeida, F. Kastensmidt, È. Cota, M. Lubaszewski and M. Hervé</i>	61
 Session 4 — Microprocessors and Multiprocessors	
Evaluating Alpha-Induced Soft Errors in Embedded Microprocessors <i>P. Rech, S. Gerardin, A. Paccagnella, P. Bernardi, M. Grosso, M. Sonza Reorda and D. Appello</i>	69
Enhanced Self-Configurability and Yield in Multicore Grids <i>E. Kolonis, M. Nicolaidis, D. Gizopoulos, M. Psarakis, J. H. Collet and P. Zajac</i>	75
Online Error Detection and Correction of Erratic Bits in Register Files <i>X. Vera, J. Abella, J. Carretero, P. Chaparro and A. González</i>	81
 Session 5 — Soft Errors and FPGAs	
Application-Oriented SEU Sensitiveness Analysis of Atmel Rad-Hard FPGAs <i>N. Battezzati, F. Decuzzi, M. Violante and M. Briet</i>	89
Exploiting Embedded FPGA in On-Line Software-Based Test Strategies for Microprocessor Cores <i>M. Grosso and M. Sonza Reorda</i>	95
Evaluating Large Grain TMR and Selective Partial Reconfiguration for Soft Error Mitigation in SRAM-based FPGAs <i>J. Rodrigo Azambuja, F. Sousa, L. Rosa and F. Lima Kastensmidt</i>	101
 Session 6 — Memories SEU Tolerance and Characterization	
Novel DRAM Mitigation Technique <i>A. Bougerol, F. Miller and N. Buard</i>	109
SRAM Cell Design Using Tri-State Devices for SEU Protection <i>Y. Shiyonovskii, F. Wolff and C. Papachristou</i>	114
Critical Charge Characterization in 6-T SRAMs During Read Mode <i>S. Bota, G. Torrens, B. Alorda and J. Segura</i>	120
 Special Session 1	
Panel: Realistic Low Power Design: Let Errors Occur and Correct them Later or Mitigate Errors <i>via</i> Design Guardbanding and Process Control? <i>J. Abraham, A. Singh, E. Maricau, R. Kumar and C. Papachristou</i>	129
 Session 7 — Soft Errors Tolerance	
A Fast Error Correction Technique for Matrix Multiplication Algorithms <i>C. Argyrides, C. A. L. Lisboa, D. K. Pradhan and L. Carro</i>	133

Soft Error Detection and Correction for FFT Based Convolution Using Different Block Lengths <i>P. Reviriego, J. Antonio Maestro, A. O'Donnell and C. J. Bleakley</i>	138
In-Depth Analysis of Digital Circuits Against Soft Errors for Selective Hardening <i>M. García-Valderas, M. Portela-García, C. López-Ongil and L. Entrena</i>	144
 Special Session 2	
DFx for Massively Multiprocessors <i>X. Vera</i>	153
Designing Dependable Multicore System with Unreliable Components <i>V. Chandra</i>	154
Variability and Reliability-Aware Application Tasks Scheduling and Power Control (Voltage and Frequency Scaling) in the Future Nanoscale Multiprocessors System on Chip <i>G. Bizot, N.-E. Zergainoh and N. Nicolaidis</i>	155
 Session 8 — Coding Techniques	
Concurrent Checking with Split-Parity Codes <i>M. Richter and M. Goessel</i>	159
Multilinear Codes for Robust Error Detection <i>Z. Wang, M. Karpovsky and B. Sunar</i>	164
Error Detection in 2-D Discrete Wavelet Lifting Transforms <i>S.-H. Hu and Jacob A. Abraham</i>	170
 Special Session 3	
Highs and Lows of Radiation Testing <i>D. Alexandrescu, A.-L. Lhomme-Perrot, E. Schaefer and C. Beltrando</i>	179
A Generic Platform for Remote Accelerated Tests and High Altitude SEU Experiments on Advanced ICs: Correlation with MUSCA SEP3 Calculations <i>G. Hubert, R. Velazco and P. Peronnard</i>	180
Using Test Infrastructures for (Remote) Online Evaluation of the Sensitivity to SEUs of FPGAs <i>A. V. Fidalgo, G. R. Alves, Manuel C. Felgueiras and M. G. Gericota</i>	181
 Session 9 — Posters	
Briefing Power/Reliability Optimization in Embedded Software Design <i>F. Vargas, C. A. Rocha, B. Pianta, M. Portela García, C. López Ongil, M. García Valderas and L. Entrena</i>	185
Linear and Nonlinear MISR Operations for Safety and Security in Automotive Applications <i>P. Duplys and E. Böhl</i>	187
FPGA-Based Testing Strategy for Cryptographic Chips: A Case Study on Elliptic Curve Processor for RFID Tags <i>J. Fan, M. Knežević, D. Karaklajić, R. Maes, V. Rozić, L. Batina and I. Verbauwhede</i>	189
Error Detection in Addition Chain Based ECC Point Multiplication <i>S. Pontarelli, G. C. Cardarilli, M. Re and A. Salsano</i>	192

Detectability Analysis of Small Delays Due to Resistive Opens Considering Process Variations <i>J. L. García-Gervacio and V. Champac</i>	195
Controllability and Observability in Mixed Signal Cores <i>J. Rocha, N. Dias, Â. Monteiro, A. Neves, G. Santos, M. Santos and J. P. Teixeira</i>	198
A Fault Tolerant Journalized Stack Processor Architecture <i>A. Ramazani, M. Amin, F. Monteiro, C. Diou and A. Dandache</i>	201
Pseudo-Random Number Generation Applied to Robust Modern Cryptography: A New Technique for Block Ciphers <i>A. Jiménez-Horas, E. San Millán, C. López-Ongil, M. Portela-García, M. García-Valderas and L. Entrena</i>	203
An Input Vector Monitoring Concurrent BIST Scheme Exploiting “X” Values <i>I. Voyiatzis, D. Gizopoulos and A. Paschalis</i>	206
Analysis of the Extra Delay on Interconnects Caused by Resistive Opens and Shorts <i>P. Maqueda and J. Rius</i>	208
C-testable S-box Implementation for Secure Advanced Encryption Standard <i>H. Rahaman, J. Mathew, A. Jabir and D. K. Pradhan</i>	210
Fault Injection-Based Evaluation of a Synchronous NoC Router <i>A. Eghbal, P. M. Yaghini, H. Pedram and H. R. Zarandi</i>	212
Session 10 — Fault-Tolerance Techniques	
A Low-Cost Fault-Tolerant Technique for Carry Look-Ahead Adder <i>A. Namazi, Y. Sedaghat, S. Ghassem Miremadi and A. Ejlali</i>	217
Delay-Fault Tolerance to Power Supply Voltage Disturbances Analysis in Nanometer Technologies <i>J. Semião, J. Freijedo, J. Rodriguez-Andina, F. Vargas, M. Santos, I. Teixeira and P. Teixeira</i>	223
Designing Fault Tolerant FSM by Nano-PLA <i>S. Baranov, I. Levin, O. Keren and M. Karpovsky</i>	229
Session 11 — Field Testing and Self-Adaptation	
Design Techniques and Tradeoffs in Implementing Non-Destructive Field Test Using Logic BIST Self-Test <i>A. Dutta, M. Shah, G. Swathi and R. A. Parekhji</i>	237
On-Line Characterization and Reconfiguration for Single Event Upset Variations <i>K. M. Zick and J. P. Hayes</i>	243
Aggressively Voltage Overscaled Adaptive RF Systems Using Error Control at the Bit and Symbol Levels <i>J. Natarajan, G. Kumar, S. Sen, M. M. Nisar, D. Lee and A. Chatterjee</i>	249

Session 12 — Encoders, Checkers and Fault Secureness

An Effective Fast and Small-Area Parallel-Pipeline Architecture for OTM-Convolutional Encoders 257

H. Jaber, F. Monteiro and A. Dandache

Ultra Low Cost Asynchronous Handshake Checker 262

S. Zeidler, M. Ehrig, M. Krštić, M. Augustin, C. Wolf and R. Kraemer

ATPG-Based Grading of Strong Fault-Secureness 269

M. Hunger, S. Hellebrand, A. Czutro, I. Polian and B. Becker

Author Index